

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1680	PRIORITY SERIAL NO. 09/512,968	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.		
					PRIORITY FILING DATE February 24, 2000	PRIORITY GROUP 2858	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa			
VN	AB	4,754,555	7/5/88	Stillman			
VN	AC	5,475,317	12/12/95	Smith			
VN	AD	5,495,667	3/5/96	Farnworth et al.			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE	S/N: 09/032,184; Filed 2/27/98; Alram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/99;					
		Original Application filed 2/27/98; Pending Claims.					
VN	AF	Advertisement for Probe Technology; www.idinet.com ; Interconnect Devices, Inc., 1 page; 3/6/98					
VN	AG	Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98					
VN	AH	Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html ; Rika Densi America, Inc.; 1 page; 2/4/98.					
VN	AI	Product Description for Test Centers, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Densi America, Inc.; 1 page; 2/4/98.					
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/io.htm#b1303 ; Rika Densi America, Inc.;					
		1 page; 2/4/98.					
VN	AK	Product Description for Ball Grid Probe B1303-C3; www.testprobe.com/products/io.htm#b1303 ; Rika Densi America, Inc.; 1 page; 2/4/98.					
VN	AL	Product Description for Test Socket Contacts; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98					
<u>EXAMINER</u>	<u>Mark Nguyen</u>		<u>DATE CONSIDERED</u>		<u>02/07/2002</u>		
<u>*EXAMINER:</u> Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.				
				FILING DATE April 3, 2001		GROUP 2858		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
<u>VN</u>	AA	5,378,311	1/3/95	Nagayama et al.				
	AB							
	AC							
	AD							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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<u>EXAMINER</u> <u><i>Mark Nguyen</i></u>				<u>DATE CONSIDERED</u> <u>02/07/2002</u>				
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